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Substitute for Form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Sheet 1 of 1

Application #	10/520,656
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First Inventor	BOSSI
Art Unit	1743
Examiner	
Docket #	P08538US00/MP

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Exam. Initial*	Country-Number-Kind	Publ. Date MM-DD-YYYY	Name Patentee or Applicant	Relevance Passages/Figs.	Trans- lation

NON PATENT LITERATURE DOCUMENTS

Exam. Initial*	Include NAME of the author (in CAPS), Title of Article/Item, Date, Page(s), Volume-Issue No., Publisher, City and/or Country where published	Translation
/D.K./	Steven J. Doherty and William L. Winniford, "Rapid On-Line Analysis Using A Micromachined Gas Chromatograph Coupled To A Bench-Top Quadrupole Mass Spectrometer," <i>LC-GC</i> 12 (1994): 846-850	
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/D.K./	Manz et al., <i>Adv. In Chromatog.</i> (1993), 33, 1-66	

Examiner Signature	/Dean Kwak/	Date Considered	01/07/2009
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* Examiner: Initial if considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.